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+38 (057) 714 26 54

Waveline W40

Mobile measurement of common surface parameters with reference plane probes



Waveline W40 with optional MS300 measuring station, PC and accessories

System features

- Handy traverse unit for a wide range of different measuring tasks
- Integrated start button for one-handed operation
- Optional, compact measuring station, can be used in the measuring room or in production
- Solves all common roughness and waviness measurement tasks
- Supports reference plane and skid probes
- Motorized probe lowering for automatic positioning and positioning and lifting after measurement
- Measurement in all positions and orientations, including upwards
- Variable measuring speed
- PC-based evaluation with Evovis Mobile Standard
- All current standards including the new ISO 21920 series of standards
- Flexible program design and logging
- Export of characteristic values and profiles, optional statistical interfaces
- Large range of probes



Mobile measurement of roughness and waviness



Waveline W40 with optional height measuring stand HS300



Measurement in any position, even upwards

Technical data

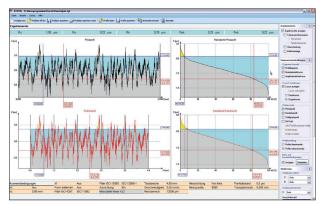
Max. traverse length	20 mm
Probe lowering	4 mm
Guide accuracy	0.2 μm/20 mm
Measurement speed Positioning speed	0.2 – 2 mm/s 0.2 – 3 mm/s
Measuring range/resolution	±300 μm/1 nm*
Interface	USB-C
Probe connection	TK probe (6-pin)
Internal alignment range	±2°
Measurement position	Any position, also upwards**

^{*} across the entire measuring range

Sets

Order number	Description
721200	Traverse unit Xmove 20, Evovis Mobile Standard software, TS1 KE2/90 T1.9 D4/30 probe arm with storage box, power adapter with cable and mains adapter, case, tools
728825	Traverse unit Xmove 20, Evovis Mobile Standard software, power adapter with cable and mains adapter, case, tools

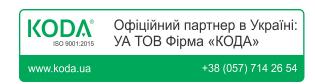
Evovis Mobile measurement and evaluation software



Interactive profile analysis

The Evovis Mobile measurement and evaluation software offers a standardized user interface for roughness measurement with clearly understandable operating logic and extensive assistance functions for the design of individual measurement applications. It has comprehensive options for documenting measurement results.

- All common surface parameters in accordance with ISO 21920, ISO 4287 and other ISO and national standards
- Integrated help for parameters
- Wizard for selecting measurement conditions
- Individual, free design of logs
- Simple creation and management of templates
- Automatic, electronic archiving of logs





^{**} depending on the probe